

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity Approved Component

IECQ Certificate No.: IECQ-C ULTW 20.0001
CB Certificate No.: 50600349 AQP

Schedule Number: IECQ-C ULTW 20.0001-S Rev No.: 1 Revision Date: 2020/01/02 Page 1 of 5

Approval Scope

Table 1 Resistance Range & Electrical Characteristics

Туре	T.C.R (PPM/℃)	Max. Working Voltage	Max. Over- Ioad Voltage	Operating Temperature (Temp. Range)(℃)		Insulation Resistance	Power Rating	Resistance Range(Ω)		
				Min.	Max.		at 70℃	F(±1%)	G(±2%)	J(±5%)
RLM12	±50	(P*R) ^{1/2}	5 X rated power for 5 sec	-55	170	over 100MΩ	1/4W	10mΩ-50mΩ	10mΩ-50mΩ	10mΩ-50mΩ
						over 100MΩ	1/2W	10mΩ-50mΩ	10mΩ-50mΩ	10mΩ-50mΩ
						over 100MΩ	1W	10mΩ-50mΩ	10mΩ-50mΩ	10mΩ-50mΩ
RLM20	±50	(P*R) ^{1/2}	5 X rated power for 5 sec	-55	170	over 100MΩ	1/2W	2mΩ~50mΩ	2mΩ~50mΩ	2mΩ~50mΩ
						over 100MΩ	3/4W	2mΩ~50mΩ	2mΩ~50mΩ	2mΩ~50mΩ
						over 100MΩ	1W	2mΩ~50mΩ	2mΩ~50mΩ	2mΩ~50mΩ
						over 100MΩ	3/2W	2mΩ~50mΩ	2mΩ~50mΩ	2mΩ~50mΩ
RLM25	±50	(P*R) ^{1/2}	5 X rated power for 5 sec	-55	170	over 100MΩ	1W	2mΩ~50mΩ	2mΩ~50mΩ	2mΩ~50mΩ
						over 100MΩ	3/2W	2mΩ~15mΩ	2mΩ~15mΩ	2mΩ~15mΩ
						over 100MΩ	2W	2mΩ~10mΩ	2mΩ~10mΩ	2mΩ~10mΩ
	±275	(P*R) ^{1/2}	5 X rated power for 5 sec	-55	170	over 100MΩ	1W	1mΩ	1mΩ	1mΩ
						over 100MΩ	3/2W	1mΩ	1mΩ	1mΩ
						over 100MΩ	2W	1mΩ	1mΩ	1mΩ

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. www.iecq.org





covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity Approved Component

IECQ Certificate No.: IECQ-C ULTW 20.0001
CB Certificate No.: 50600349 AQP

Schedule Number: IECQ-C ULTW 20.0001-S Rev No.: 1 Revision Date: 2020/01/02 Page 2 of 5

		Table 2	Part Numb	er	
RLM 12 Item Series No.	<u>F</u> Resistance tolerance	<u>T</u> Packaging	<u>S</u> Power Rating	<u>M</u> Metal	R010 Resistance
12:1206 (3216)	F:±1% G:±2% J:±5%	T: Paper	A=1/4W S=1/2W C=1W	M=Metal	e.g: R010=10m Ω R050=50m Ω
RLM 20 Item Series No.	<u>F</u> Resistance tolerance	<u>E</u> Packaging	<u>C</u> Power Rating	R020 Resistance	
20:2010 (5025)	F:±1% G:±2% J: ±5%	E:Embossed tape	S=1/2W I=3/4W C=1W D=3/2W	e.g : R003=3m Ω R050=50m Ω	
RLM 25 Item Series No.	<u>F</u> Resistance tolerance	<u>E</u> Packaging	<u>C</u> Power Rating	R020 Resistance	
25:2512 (6432)	F:±1% G:±2% J: ±5%	E:Embossed tape	C=1W D=3/2W E=2W	e.g : R001=1m Ω R050=50m Ω	

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. www.iecq.org





covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity

Approved Component

IECQ Certificate No.: IECQ-C ULTW 20.0001
CB Certificate No.: 50600349 AQP

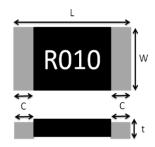
Schedule Number: IECQ-C ULTW 20.0001-S Rev No.: 1 Revision Date: 2020/01/02 Page 3 of 5

1.1 Outline Drawing and Dimension

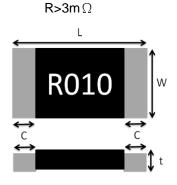
The outline drawing and dimension is listed as Table 3.

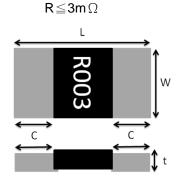
Table 3 Outline Drawing and Dimension

RLM12

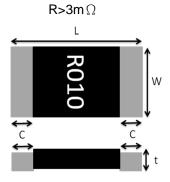


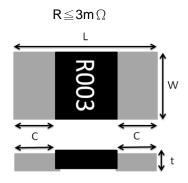
RLM20





RLM25





This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. www.iecq.org

DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan





covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity Approved Component

IECQ Certificate No.: IECQ-C ULTW 20.0001
CB Certificate No.: 50600349 AQP

Schedule Number: IECQ-C ULTW 20.0001-S Rev No.: 1 Revision Date: 2020/01/02 Page 4 of 5

					unit:mm
Style	L	w	С	t	Material
RLM12	3.2±0.2	1.6±0.2	0.5 ± 0.3	0.6 ± 0.2	Madel - Allen
DI MOO	5.0±0.2	2.5±0.2	1.5±0.3(R≦3mΩ)		Metal : Alloy Over Coating : molding Compound UL-94V grade
RLM20			0.6±0.3(R>3mΩ)	0.0 ±0.2	
RLM25	6.4±0.2	3.2±0.2	2.0±0.2(R≦3mΩ)	0.6 ±0.2	
			0.9±0.2(R>3mΩ)		

1.2 Related Documents

IECQ 03-1, Rule of Procedure - Part 1: General Requirements for all IECQ Schemes

IECQ 03-3, Rule of Procedure – Part 3: IECQ Approved Component Products, Related Materials & Assemblies Scheme

IECQ 03-3-2: Rule of Procedure – Part 3-2: IECQ Approved Component Products, Related Materials & Assemblies Scheme, IECQ Approved Component – Automotive Qualification Program (IECQ AC-AQP)

AEC-Q200 REV D, Stress Test Qualification for Passive Components

AEC-Q200-004A Resistance Measurement Method

AEC-Q200-002B Human Body Model Electrostatic Discharge Test

AEC-Q200-005A Board Flex Test

AEC-Q200-006A Terminal Strength (SMD)/Shear Stress Test

JEDEC JESD22-A104D Temperature Cycling

JEDEC JEP 140 Beaded Thermocouple Temperature Measurement of Semiconductor Package

JEDEC JEP 153A Characterization and Monitoring Thermal Stress Test Oven Temperatures

MIL-STD-883K Method 2009 Test methods standard microcircuits



covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity Approved Component

IECQ Certificate No.: IECQ-C ULTW 20.0001
CB Certificate No.: 50600349 AQP

Schedule Number: IECQ-C ULTW 20.0001-S Rev No.: 1 Revision Date: 2020/01/02 Page 5 of 5

JEDEC JESD22-B100B Physical Dimensions

MIL-STD-202H, Test Method Standard, Electronic and Electrical Component Part

EIA/IPC/JEDEC J-STD-002D, Solderability Tests for Component Leads, Terminations, Lugs, Terminals and Wires

ASTM-B-809-95(2013): Standard Test Method for Porosity in Metallic Coatings by Humid Sulfur Vapor ("Flowers-of-Sulfur")

IEC 60115-1 Edition 4.0: Fixed Resistors for Use in Electronic Equipment - Part 1: Generic Specification

UL-94: Flammability

